

# FQP10N50CF / FQPF10N50CF N-Channel QFET® FRFET® MOSFET

500 V, 10 A, 610 mΩ



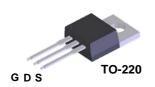
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.



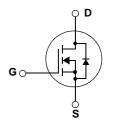
• 10 A, 500 V,  $R_{DS(on)}$  = 610 m $\Omega(Max.)$  @ $V_{GS}$  = 10 V,  $I_D$  = 5 A

March 2013

- Low Gate Charge (Typ. 43 nC)
- Low C<sub>rss</sub> (Typ. 16 pF)
- 100% Avalanche Tested
- · Fast Recovery Body Diode







## **Absolute Maximum Ratings**

Symbol	Parameter		FQP10N50CF	FQPF10N50CF	Unit	
V <sub>DSS</sub>	Drain-Source Voltage			5	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		10	10*	Α	
	- Continuous (T <sub>C</sub> = 100°C)		6.35	6.35*	Α	
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	40	40*	Α
V <sub>GSS</sub>	Gate-Source voltage			±	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)			3	mJ	
I <sub>AR</sub>	Avalanche Current		(Note 1)	10		Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		14.3		mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns	
P <sub>D</sub>	Power Dissipation	(T <sub>C</sub> = 25°C)		143	48	W
		- Derate above 25	5°C	1.14	0.38	W/°C
T <sub>J,</sub> T <sub>STG</sub>	Operating and Storage Temperature Range			-55 to	°C	
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	°C	

<sup>\*</sup>Drain current limited by maximum junction temperature

### **Thermal Characteristics**

Symbol	Parameter	FQP10N50CF	FQPF10N50CF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.87	2.58	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FQP10N50CF	FQP10N50CF	TO-220	-	-	50
FQPF10N50CF	FQPF10N50CF	TO-220F	-	-	50

# **Electrical Characteristics** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter Conditions		Min	Тур	Max	Units
Off Charac	teristics	-		!		
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}, T_J = 25^{\circ}\text{C}$	500			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.5		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V			10	μА
		V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C			100	μА
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Charac	teristics			·		
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 5 A		0.5	0.61	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 5 A (Note 4)		15		S
Dynamic C	haracteristics			II.	ı	
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		1610	2096	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		177	230	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	7		16	24	pF
	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 10 A		29	67	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		80	170	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			141	290	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		80	165	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 10 A		43	56	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		7.5		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		18.5		nC
Drain-Sour	ce Diode Characteristics and Maximun	n Ratings				
I <sub>S</sub> Maximum Continuous Drain-Source Diode		de Forward Current			10	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Fe	orward Current			40	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 10 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 10 A		50		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s $ (Note 4)		0.1		μС

#### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 7 mH, I $_{AS}$  = 10 A, V $_{DD}$  = 50 V, R $_{G}$  = 25  $\Omega$ , Starting T $_{J}$  = 25°C
- 3.  $I_{SD} \le$  10 A, di/dt  $\le$  200 A/ $\mu$ s,  $V_{DD} \le$  BV $_{DSS}$ , Starting  $T_J$  = 25°C
- 4. Pulse Test: Pulse width  $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

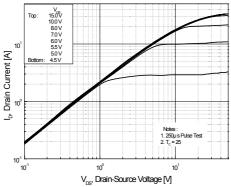
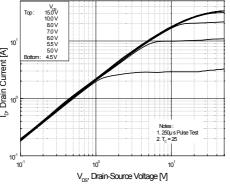


Figure 3. On-Resistance Variation vs. **Drain Current and Gate Voltage** 



Notes: 1. V<sub>Ds</sub> = 40V 2. 250µs Pulse Test 10<sup>-1</sup> 2

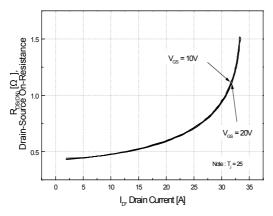
 $V_{_{\!G\!S'}}$  Gate-Source Voltage [V]

Figure 2. Transfer Characteristics

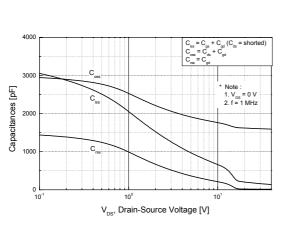
150°C

l<sub>p</sub>, Drain Current [A]

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



**Figure 5. Capacitance Characteristics** 



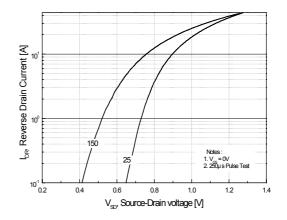
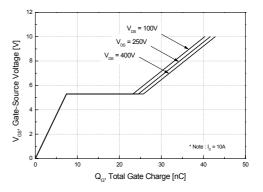


Figure 6. Gate Charge Characteristics



# Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

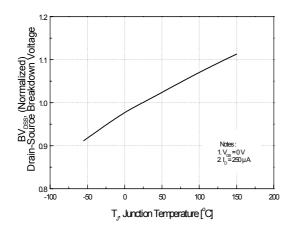


Figure 9-1. Maximum Safe Operating Area for FQP10N50CF

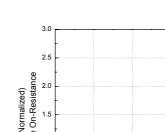


Figure 8. On-Resistance Variation

vs. Temperature

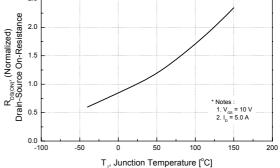


Figure 9-2. Maximum Safe Operating Area for FQPF10N50CF

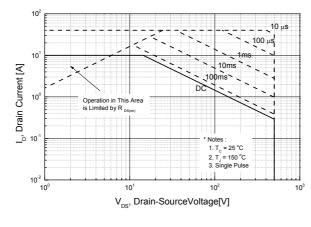
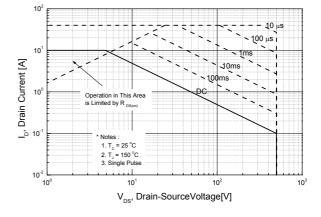
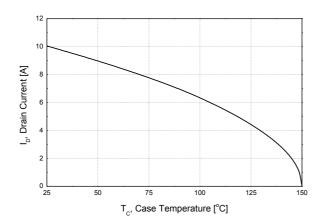


Figure 10. Maximum Drain Current vs. Case Temperature





# **Typical Performance Characteristics (Continued)**

Figure 11-1. Transient Thermal Response Curve for FQP10N50CF

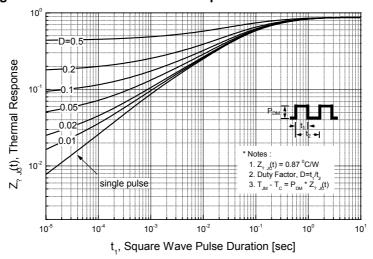
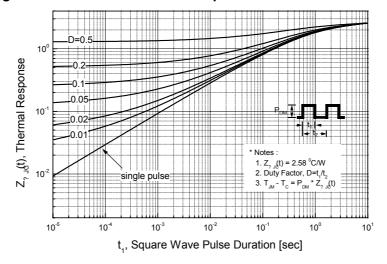
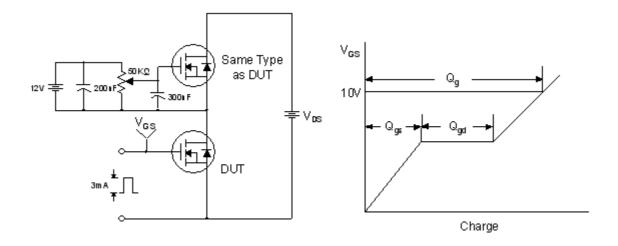


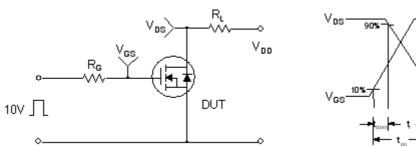
Figure 11-2. Transient Thermal Response Curve for FQPF10N50CF

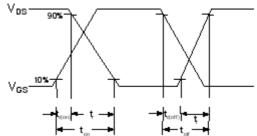


## **Gate Charge Test Circuit & Waveform**

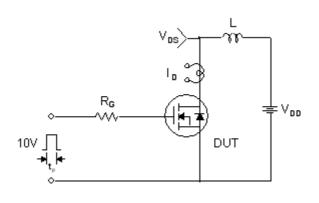


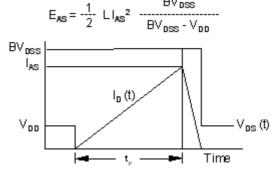
#### **Resistive Switching Test Circuit & Waveforms**



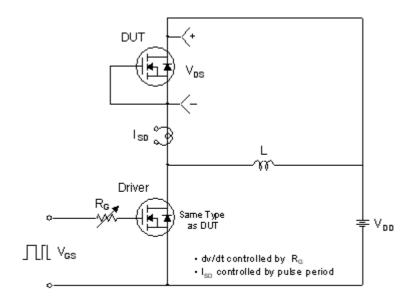


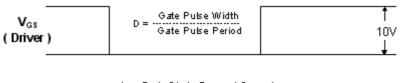
### **Unclamped Inductive Switching Test Circuit & Waveforms**

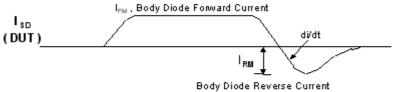


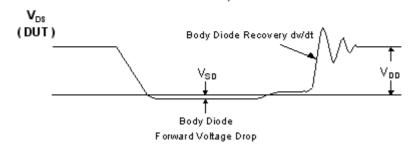


### Peak Diode Recovery dv/dt Test Circuit & Waveforms



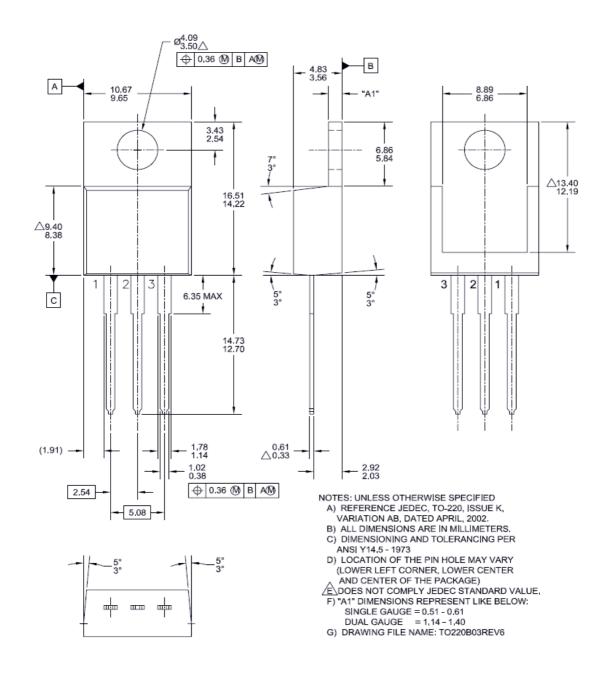






## **Mechanical Dimensions**

# TO-220



Dimensions in Millimeters

# **Mechanical Dimensions** TO-220F 2.742.34 10.36 A 9.96 φ<sup>3.28</sup> 7.00 3.40 3.08 (0.70) 3.20 SEE NOTE "F" SEE NOTE "F" 6.88 6.48 1 X 45° 16.07 ∕B\ 15.67 16.00 15.60 (3.23) B 3 1.47 2.96 1.24 2.14 2.56 0.90 10.05 0.70 $\oplus$ 0.50 (M) A 9.45 30° 0.45 0.60 0.25 0.45 2.54 2.54 NOTES: A. EXCEPT WHERE NOTED CONFORMS TO EIAJ SC91A. DOES NOT COMPLY EIAJ STD. VALUE. C. ALL DIMENSIONS ARE IN MILLIMETERS. D. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS. E. DIMENSION AND TOLERANCE AS PER ASME V14 5 1004 4.90 <u>/B</u>\ 4.50 Y14.5-1994. F. OPTION 1 - WITH SUPPORT PIN HOLE. OPTION 2 - NO SUPPORT PIN HOLE. G. DRAWING FILE NAME: TO220M03REV3 **Dimensions in Millimeters**





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Rev. 164